



# Table of contents

Monday 26 September 2016 .....	1
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# Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D Characterisation and Imaging with Ion Beams | (smr 2856)

## Monday 26 September 2016

### DAY 1 - LB (Euler Lecture Hall) (08:00-20:30)

time	title	presenter
08:00	REGISTRATION	
08:30	Opening of the Workshop and Introduction of the participants	
09:30	Overview of the ICTP and IAEA relevant activities	SCANDOLO, Sandro SIMON, Aliz
10:00	External nuclear microprobe specificities and challenges	CALLIGARO, Thomas
11:00	FINANCIAL/ADMINISTRATIVE FORMALITIES - LUNCH BREAK	
14:00	Implementation of External Ion Beam Imaging	CALLIGARO, Thomas
15:00	Beyond Elemental Analysis: Elemental, Chemical and Molecular Imaging	WEBB, Roger
16:00	Coffee break	
16:30	Total IBA: Synergistic treatment of data from multiple IBA techniques (I)	BARRADAS, Nuno P.
19:00	Informal reception	